

SOIC_N QUALIFICATION RESULTS			
TEST	CONDITIONS	SAMPLE SIZE	RESULTS
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	231	Pass
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	231	Pass
Autoclave (AC)*	JEDEC <i>JESD22-A102</i>	231	Pass
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	77	Pass
Solder Heat Resistance (SHR)*	<i>ADI-0049</i>	60	Pass

*Preconditioned per JEDEC/IPC J-STD-020

SOIC_W QUALIFICATION RESULTS			
TEST	CONDITIONS	SAMPLE SIZE	RESULTS
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	231	Pass
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	231	Pass
Autoclave (AC)*	JEDEC <i>JESD22-A102</i>	231	Pass
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	45	Pass
Solder Heat Resistance (SHR)*	<i>ADI-0049</i>	30	Pass

*Preconditioned per JEDEC/IPC J-STD-020